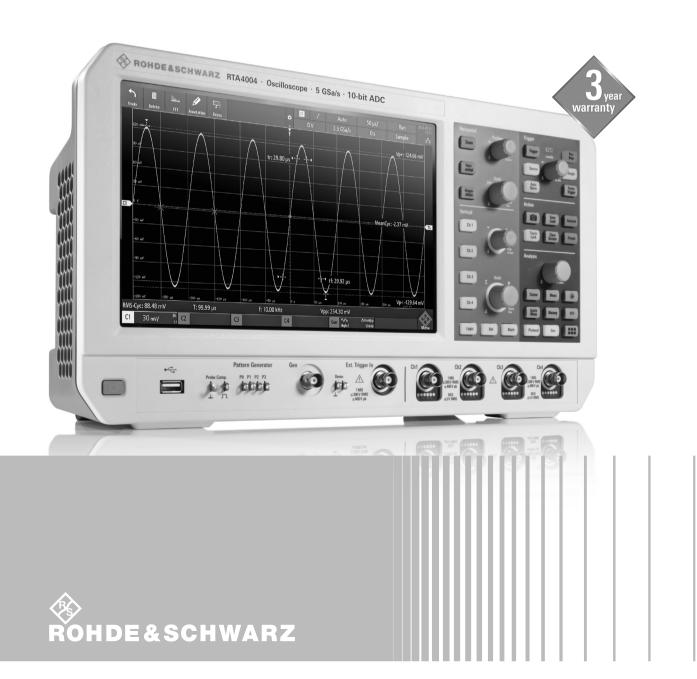
# R&S®RTA4000 Oscilloscope Specifications



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#### **Definitions**

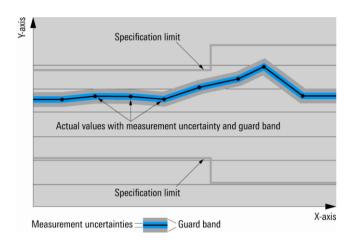
#### Genera

Product data applies under the following conditions:

- Three hours storage at ambient temperature followed by 30 minutes warm-up operation
- Specified environmental conditions met
- · Recommended calibration interval adhered to
- · All internal automatic adjustments performed, if applicable

#### Specifications with limits

Represent warranted product performance by means of a range of values for the specified parameter. These specifications are marked with limiting symbols such as <,  $\le$ ,  $\ge$ ,  $\pm$ , or descriptions such as maximum, limit of, minimum. Compliance is ensured by testing or is derived from the design. Test limits are narrowed by guard bands to take into account measurement uncertainties, drift and aging, if applicable.



#### Specifications without limits

Represent warranted product performance for the specified parameter. These specifications are not specially marked and represent values with no or negligible deviations from the given value (e.g. dimensions or resolution of a setting parameter). Compliance is ensured by design.

#### Typical data (typ.)

Characterizes product performance by means of representative information for the given parameter. When marked with <, > or as a range, it represents the performance met by approximately 80 % of the instruments at production time. Otherwise, it represents the mean value.

#### Nominal values (nom.)

Characterize product performance by means of a representative value for the given parameter (e.g. nominal impedance). In contrast to typical data, a statistical evaluation does not take place and the parameter is not tested during production.

#### Measured values (meas.)

Characterize expected product performance by means of measurement results gained from individual samples.

#### Uncertainties

Represent limits of measurement uncertainty for a given measurand. Uncertainty is defined with a coverage factor of 2 and has been calculated in line with the rules of the Guide to the Expression of Uncertainty in Measurement (GUM), taking into account environmental conditions, aging, wear and tear.

Device settings and GUI parameters are indicated as follows: "parameter: value".

Typical data as well as nominal and measured values are not warranted by Rohde & Schwarz.

In line with the 3GPP/3GPP2 standard, chip rates are specified in Mcps (million chips per second), whereas bit rates and symbol rates are specified in Mbps (million bits per second), kbps (thousand bits per second), Msps (million symbols per second) or ksps (thousand symbols per second), and sample rates are specified in Msample/s (million samples per second). Mcps, Mbps, Msps, ksps and Msample/s are not SI units.

### Base unit

### **Vertical system**

Input channels	R&S®RTA4004	4 channels	
Input impedance		50 Ω ± 1.5 % (meas.)	
		1 MΩ ± 1 %    14 pF ± 1 pF (meas.)	
Analog bandwidth (-3 dB)	at 50 Ω input impedance		
	R&S®RTA4004	> 200 MHz	
	R&S®RTA4004 with -B243 option	> 350 MHz	
	R&S®RTA4004 with -B245 option	> 500 MHz	
	R&S®RTA4004 with -B2410 option	> 1 GHz	
	at 1 MΩ input impedance		
	R&S®RTA4004 with	> 200 MHz (meas.)	
	R&S®RTA4004 with -B243 option	> 350 MHz (meas.)	
	R&S®RTA4004 with -B245 option	> 500 MHz (meas.)	
	R&S®RTA4004 with -B2410 option	> 500 MHz (meas.)	
Lower frequency limit (–3 dB)	at AC coupling	< 5 Hz (meas.)	
Analog bandwidth limits	at 50 Ω input impedance	(	
	R&S®RTA4004	20 MHz, 100 MHz	
	R&S®RTA4004 with -B243 option	20 MHz, 100 MHz, 200 MHz	
	R&S®RTA4004 with -B245 option	20 MHz, 100 MHz, 200 MHz, 350 MHz	
	R&S®RTA4004 with -B2410 option	20 MHz, 100 MHz, 200 MHz, 350 MHz,	
	NGO NIA4004 WIIII-D2410 OPIIOII	20 MHz, 100 MHz, 200 MHz, 350 MHz,	
	at 1 MO input impadance	JUU IVITZ	
	at 1 MΩ input impedance	20 MHz 400 MHz	
	R&S®RTA4004	20 MHz, 100 MHz	
	R&S®RTA4004 with -B243 option	20 MHz, 100 MHz, 200 MHz	
	R&S®RTA4004 with -B245 option and	20 MHz, 100 MHz, 200 MHz, 350 MHz	
	R&S®RTA4004 with -B2410 option		
Rise time (calculated)	R&S®RTA4004	< 1.75 ns	
	R&S®RTA4004 with -B243 option	< 1 ns	
	R&S®RTA4004 with -B245 option	< 700 ps	
	R&S®RTA4004 with -B2410 option	< 350 ps	
Vertical resolution		10 bit, up to 16 bit with high resolution	
		decimation	
DC gain accuracy	offset and position = 0		
, g.,,	maximum operating temperature change of ±5 °C after self-alignment		
		±1 %	
	input sensitivity > 5 mV/div		
	input sensitivity > 5 mV/div		
	input sensitivity	±1.5 %	
	input sensitivity ≤ 5 mV/div to ≥ 1 mV/div	±1.5 %	
Input coupling	input sensitivity	±1.5 % ±2.5 %	
· · · · · · · · · · · · · · · · · · ·	input sensitivity ≤ 5 mV/div to ≥ 1 mV/div input sensitivity < 1 mV/div	±1.5 %  ±2.5 %  DC, AC, GND	
Input coupling Input sensitivity	input sensitivity ≤ 5 mV/div to ≥ 1 mV/div input sensitivity < 1 mV/div  at 50 Ω	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div	
Input sensitivity	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div	
· · · · · ·	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity < 1 mV/div $\text{at } 50 \ \Omega$ at 1 M $\Omega$ at 50 $\Omega$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )	
Input sensitivity	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at	
Input sensitivity	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity < 1 mV/div $\text{at } 50 \ \Omega$ at 1 M $\Omega$ at 50 $\Omega$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )	
Input sensitivity  Maximum input voltage	input sensitivity $\leq 5 \text{ mV/div to} \geq 1 \text{ mV/div}$ input sensitivity < 1 mV/div $\text{at } 50 \ \Omega$ at 1 M $\Omega$ at 50 $\Omega$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at	
Input sensitivity  Maximum input voltage  Position range	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above	
Input sensitivity  Maximum input voltage  Position range	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 M\Omega$ at $50 \Omega$ at $1 M\Omega$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz	
Input sensitivity  Maximum input voltage  Position range	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz	
Input sensitivity  Maximum input voltage  Position range	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 M\Omega$ at $50 \Omega$ at $1 M\Omega$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div	
Input sensitivity  Maximum input voltage  Position range	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 M\Omega$ at $50 \Omega$ at $1 M\Omega$ input sensitivity $\leq 112 \text{ mV/div}$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V – 5 div × input sensitivity)  ±(10 V – 5 div × input sensitivity)	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 Ω	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $1 \text{ M}\Omega$ input sensitivity $= 112 \text{ mV/div}$ $\geq 33.8 \text{ mV/div}$ $= 33.6 \text{ mV/div}$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V – 5 div × input sensitivity)	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 Ω	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50 Ω  at 1 MΩ  at 50 Ω  at 1 MΩ  input sensitivity  input sensitivity  ≥ 112 mV/div to 1 V/div  ≥ 33.8 mV/div to 111 mV/div  0.5 mV/div to 33.6 mV/div  input sensitivity	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V – 5 div × input sensitivity)  ±(10 V – 5 div × input sensitivity)  ±(2 V – 5 div × input sensitivity)	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 Ω	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div} \text{ to } 1 \text{ V/div}$ $\geq 33.8 \text{ mV/div} \text{ to } 111 \text{ mV/div}$ $0.5 \text{ mV/div} \text{ to } 33.6 \text{ mV/div}$ input sensitivity $\geq 515 \text{ mV/div} \text{ to } 10 \text{ V/div}$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V – 5 div × input sensitivity)  ±(10 V – 5 div × input sensitivity)  ±(2 V – 5 div × input sensitivity)  ±(250 V – 5 div × input sensitivity)	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 Ω	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div} \text{ to } 1 \text{ V/div}$ $\geq 33.8 \text{ mV/div} \text{ to } 111 \text{ mV/div}$ $0.5 \text{ mV/div} \text{ to } 33.6 \text{ mV/div}$ input sensitivity $\geq 515 \text{ mV/div} \text{ to } 10 \text{ V/div}$ $\geq 50.5 \text{ mV/div} \text{ to } 510 \text{ mV/div}$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V - 5 div × input sensitivity)  ±(10 V - 5 div × input sensitivity)  ±(2 V - 5 div × input sensitivity)  ±(250 V - 5 div × input sensitivity)	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 $\Omega$ Offset range at 1 $M\Omega$	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div} \text{ to } 1 \text{ V/div}$ $\geq 33.8 \text{ mV/div} \text{ to } 111 \text{ mV/div}$ $0.5 \text{ mV/div} \text{ to } 33.6 \text{ mV/div}$ input sensitivity $\geq 515 \text{ mV/div} \text{ to } 10 \text{ V/div}$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V - 5 div × input sensitivity) ±(10 V - 5 div × input sensitivity) ±(2 V - 5 div × input sensitivity)  ±(250 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity) ±(25 V - 5 div × input sensitivity)	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 $\Omega$ Offset range at 1 $M\Omega$	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div} \text{ to } 1 \text{ V/div}$ $\geq 33.8 \text{ mV/div} \text{ to } 111 \text{ mV/div}$ $0.5 \text{ mV/div} \text{ to } 33.6 \text{ mV/div}$ input sensitivity $\geq 515 \text{ mV/div} \text{ to } 10 \text{ V/div}$ $\geq 50.5 \text{ mV/div} \text{ to } 510 \text{ mV/div}$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V - 5 div × input sensitivity)  ±(10 V - 5 div × input sensitivity)  ±(2 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(20 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 Ω  Offset range at 1 MΩ	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div} \text{ to } 1 \text{ V/div}$ $\geq 33.8 \text{ mV/div} \text{ to } 111 \text{ mV/div}$ $0.5 \text{ mV/div} \text{ to } 33.6 \text{ mV/div}$ input sensitivity $\geq 515 \text{ mV/div} \text{ to } 10 \text{ V/div}$ $\geq 50.5 \text{ mV/div} \text{ to } 510 \text{ mV/div}$ $0.5 \text{ mV/div} \text{ to } 50 \text{ mV/div}$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V - 5 div × input sensitivity)  ±(10 V - 5 div × input sensitivity)  ±(2 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(0.5 % ×  offset  + 0.1 div × input sensitivity + 0.5 mV)	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 Ω  Offset range at 1 MΩ	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div} \text{ to } 1 \text{ V/div}$ $\geq 33.8 \text{ mV/div} \text{ to } 111 \text{ mV/div}$ $0.5 \text{ mV/div} \text{ to } 33.6 \text{ mV/div}$ input sensitivity $\geq 515 \text{ mV/div} \text{ to } 10 \text{ V/div}$ $\geq 50.5 \text{ mV/div} \text{ to } 510 \text{ mV/div}$ $0.5 \text{ mV/div} \text{ to } 50 \text{ mV/div}$	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V - 5 div × input sensitivity)  ±(10 V - 5 div × input sensitivity)  ±(2 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(0.5 % ×  offset  + 0.1 div × input sensitivity + 0.5 mV)  ±(DC gain accuracy ×  reading - net	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 $\Omega$ Offset range at 1 $M\Omega$	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div}$ to $1 \text{ V/div}$ $\geq 33.8 \text{ mV/div}$ to $111 \text{ mV/div}$ $0.5 \text{ mV/div}$ to $33.6 \text{ mV/div}$ input sensitivity $\geq 515 \text{ mV/div}$ to $510 \text{ mV/div}$ $\geq 50.5 \text{ mV/div}$ to $510 \text{ mV/div}$ $0.5 \text{ mV/div}$ to $50 \text{ mV/div}$ after adequate suppression of measurement noise by using either high-	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V - 5 div × input sensitivity)  ±(10 V - 5 div × input sensitivity)  ±(2 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(0.5 % ×   offset  + 0.1 div × input sensitivity + 0.5 mV)	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 Ω  Offset range at 1 MΩ	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at 50 Ω  at 1 MΩ  at 50 Ω  at 1 MΩ  at 50 Ω  at 1 MΩ  at 1 MΩ  input sensitivity $\geq 112 \text{ mV/div}$ $\geq 112 \text{ mV/div}$ to 1 V/div $\geq 33.8 \text{ mV/div}$ to 111 mV/div  0.5 mV/div to 33.6 mV/div  input sensitivity $\geq 515 \text{ mV/div}$ to 10 V/div $\geq 50.5 \text{ mV/div}$ to 510 mV/div  0.5 mV/div to 50 mV/div  after adequate suppression of measurement noise by using either high-resolution sampling mode or waveform	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V - 5 div × input sensitivity)  ±(10 V - 5 div × input sensitivity)  ±(2 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(0.5 % ×  offset  + 0.1 div × input sensitivity + 0.5 mV)  ±(DC gain accuracy ×  reading - net	
Input sensitivity  Maximum input voltage  Position range  Offset range at 50 Ω  Offset range at 1 MΩ	input sensitivity $\leq 5 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ input sensitivity $< 1 \text{ mV/div}$ at $50 \Omega$ at $1 \text{ M}\Omega$ at $50 \Omega$ at $1 \text{ M}\Omega$ input sensitivity $\geq 112 \text{ mV/div}$ to $1 \text{ V/div}$ $\geq 33.8 \text{ mV/div}$ to $111 \text{ mV/div}$ $0.5 \text{ mV/div}$ to $33.6 \text{ mV/div}$ input sensitivity $\geq 515 \text{ mV/div}$ to $510 \text{ mV/div}$ $\geq 50.5 \text{ mV/div}$ to $510 \text{ mV/div}$ $0.5 \text{ mV/div}$ to $50 \text{ mV/div}$ after adequate suppression of measurement noise by using either high-	±1.5 %  ±2.5 %  DC, AC, GND  0.5 mV/div to 1 V/div  0.5 mV/div to 10 V/div  5 V (RMS), max. 30 V (V <sub>p</sub> )  300 V (RMS), 400 V (V <sub>p</sub> ), derates at 20 dB/decade to 5 V (RMS) above 250 kHz  ±5 div  ±(30 V - 5 div × input sensitivity)  ±(10 V - 5 div × input sensitivity)  ±(2 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(25 V - 5 div × input sensitivity)  ±(0.5 % ×  offset  + 0.1 div × input sensitivity + 0.5 mV)  ±(DC gain accuracy ×  reading - net	

RMS noise floor at 1 MΩ (meas.)	Input sensitivity	R&S®			
	,	RTA4004	RTA4004 with	RTA4004 with	RTA4004 with
			-B243 option	-B245 option	-B2410 option
	10 V/div	226 mV	250 mV	298 mV	298 mV
	5 V/div	124 mV	132 mV	182 mV	182 mV
	2 V/div	53.1 mV	58.7 mV	81.5 mV	81.5 mV
	1 V/div	29.1 mV	32.9 mV	45.6 mV	45.6 mV
	500 mV/div	12.4 mV	13.2 mV	18.2 mV	18.2 mV
	200 mV/div	5.3 mV	5.9 mV	8.2 mV	8.2 mV
	100 mV/div	3.0 mV	3.4 mV	4.7 mV	4.7 mV
	50 mV/div	1.2 mV	1.2 mV	1.6 mV	1.6 mV
	20 mV/div	0.54 mV	0.59 mV	0.83 mV	0.83 mV
	10 mV/div	0.28 mV	0.32 mV	0.44 mV	0.44 mV
	5 mV/div	0.16 mV	0.19 mV	0.25 mV	0.25 mV
	2 mV/div	0.11 mV	0.14 mV	0.19 mV	0.19 mV
	1 mV/div	0.09 mV	0.10 mV	0.13 mV	0.13 mV
	0.5 mV/div	0.09 mV	0.10 mV	0.13 mV	0.13 mV
RMS noise floor at 50 Ω (meas.)	Input sensitivity	R&S®			
		RTA4004	RTA4004 with	RTA4004 with	RTA4004 with
			-B243 option	-B245 option	-B2410 option
	1 V/div	22.7 mV	22.8 mV	25.1 mV	31.4 mV
	500 mV/div	12.6 mV	13.7 mV	15.4 mV	19.8 mV
	200 mV/div	5.5 mV	6.2 mV	7.0 mV	9.1 mV
	100 mV/div	2.7 mV	3.0 mV	3.4 mV	4.6 mV
	50 mV/div	1.4 mV	1.6 mV	1.8 mV	2.4 mV
	20 mV/div	0.53 mV	0.58 mV	0.65 mV	0.86 mV
	10 mV/div	0.26 mV	0.28 mV	0.32 mV	0.41 mV
	5 mV/div	0.15 mV	0.18 mV	0.20 mV	0.27 mV
	2 mV/div	0.07 mV	0.09 mV	0.10 mV	0.13 mV
	1 mV/div	0.06 mV	0.07 mV	0.08 mV	0.11 mV
	0.5 mV/div	0.05 mV	0.07 mV	0.08 mV	0.11 mV

# **Horizontal system**

Timebase range		selectable between
		0.5 ns/div and 500 s/div
Channel deskew		±500 ns
Trigger offset range	minimum	memory depth
		actual sampling rate
	maximum	2 <sup>33</sup>
		actual sampling rate
Modes		normal, roll
Channel-to-channel skew		< 200 ps (meas.)
Timebase accuracy	after delivery/calibration, at +23 °C	±0.5 ppm
	during calibration interval	±1 ppm

# **Acquisition system**

Maximum realtime sampling rate	normal mode	2.5 Gsample/s
	interleaved mode,	5 Gsample/s
	if following channels are not used	
	simultaneously:	
	<ul> <li>channel 1 and channel 2</li> </ul>	
	<ul> <li>channel 3 and channel 4</li> </ul>	
	logic channels	
Memory depth per channel	normal mode	100 Msample per channel
	interleaved mode,	200 Msample per channel
	if following channels are not used	
	simultaneously:	
	<ul> <li>channel 1 and channel 2</li> </ul>	
	<ul> <li>channel 3 and channel 4</li> </ul>	
	logic channels	
Acquisition modes	sample	first sample in decimation interval
	peak detect	largest and smallest sample in decimation interval (400 ps detection)
	high resolution	average value of all samples in decimation interval
	envelope	envelope of acquired waveforms
	average	average over a series of acquired waveforms
	envelope + peak detect	envelope of acquired waveforms with active peak detect
	envelope + high resolution	envelope of acquired waveforms with active high resolution
	average + high resolution	average over a series of acquired high
		resolution waveforms
Number of averaged waveforms		2 to 100 000
Waveform acquisition rate	dot display, single channel, auto record length	up to 64 000 waveforms/s

# Trigger system

Trigger level	range	±5 div from center of screen
Trigger modes		auto, normal, single, n single
Hold-off range	time	inactive or 51.2 ns to 13.7 s
Trigger types		edge, width, video, pattern, runt, rise time, fall time, serial bus, line, timeout
Edge trigger A	trigger events	rising edge, falling edge, both edges
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option), external trigger input
	trigger coupling	DC, AC (attenuates < 10 Hz (meas.)), LF reject (attenuates < 10 kHz (meas.))
	trigger filter	HF reject (attenuates > 100 kHz (meas.)), noise reject (attenuates > 100 MHz (meas.))
	selectable trigger hysteresis	automatic, small, medium, large

Trigger A sensitivity hysteresis mode	with DC, AC, LF reject, noise reject	
automatic	1 GHz, 500 MHz, 350 MHz	$2.2  mV_{nn}$
		$> \frac{2.2  mV_{pp}}{input  sensitivity} + 1  div  (nom.)$
		(input sensitivity: [mV/div])
	200 MHz, 100 MHz	$1.5mV_{pp}$
		$> \frac{1.5  mV_{pp}}{input  sensitivity} + 0.8  div  (nom.)$
		(input sensitivity: [mV/div])
	00 MH=	0.6
	20 MHz	$> \frac{0.6  mV_{pp}}{input  sensitivity} + 0.4  div  (nom.)$
		(input sensitivity: [mV/div])
	with HF reject	
	all input sensitivities	1 div (meas.)
Edge trigger A and B	trigger events	rising edge, falling edge, both edges
	sources for A trigger	
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, logic channels from D15 to D0
		(with R&S®RTA-B1 option)
	trigger coupling of A trigger	DC
	sources for B trigger	
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, logic channels from D15 to D0
		(with R&S®RTA-B1 option)
	trigger coupling of B trigger	DC
	selectable trigger hysteresis for A and B trigger	small, medium, large
	trigger B mode	after time or after events
	trigger B minimum time	3.2 ns
	trigger B maximum time	100 s
	trigger B events	1 to 65535
Width trigger	trigger events	pulse width is smaller, greater, equal,
		unequal, inside interval, outside interval
	minimum pulse width	3.2 ns
	maximum pulse width	6.8 s
	polarity	positive, negative
	sources	
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, logic channels from D15 to D0
		(with R&S®RTA-B1 option)
	selectable trigger hysteresis	small, medium, large
Timeout trigger	trigger events	greater than timeout
	minimum timeout	3.2 ns
	maximum timeout	6.8 s
	polarity	stays high, stays low, stays high or low
	sources	
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, logic channels from D15 to D0
		(with R&S®RTA-B1 option)
	selectable trigger hysteresis	small, medium, large
Video trigger	trigger events	selectable line, all lines, even frame,
		odd frame, all frames
	supported standards	PAL, NTSC, SECAM, PAL-M, SDTV 576i,
		HDTV 720p, HDTV 1080i, HDTV 1080p
	sources	
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, ext. trigger input
	sync pulse polarity	positive, negative

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Pattern trigger	trigger events	logic condition between active channels		
	sources			
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)		
	state of channels	high, low, don't care		
	logic between channels	and/or		
	condition	true, false		
	duration condition	smaller, greater, equal, unequal, inside interval, outside interval, timeout		
	minimum duration time	3.2 ns		
	maximum duration time	6.8 s		
Runt trigger		triggers on pulse of positive, negative or either polarity that crosses one threshold but fails to cross a second threshold before crossing the first one again		
Rise time, fall time	trigger events	time between the crossing of two selectable levels is smaller, greater, equal, unequal, inside interval, outside interval		
	minimum rise time	3.2 ns		
	maximum rise time	6.8 s		
	polarity	rising edge, falling edge, both edges		
	sources			
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4		
Serial bus trigger	supported standards			
	R&S®RTA-K1 option	I <sup>2</sup> C, SSPI (two-wire, MOSI/MISO), SPI (three-wire, MOSI/MISO)		
	R&S®RTA-K2 option	UART/RS-232/RS-422/RS-485 (RX/TX)		
	R&S®RTA-K3 option	CAN/LIN		
	R&S®RTA-K5 option	audio (I <sup>2</sup> S, LJ, RJ, TDM)		
	R&S®RTA-K6 option	MIL-STD-1553		
	R&S®RTA-K7 option	ARINC 429		
External trigger input	input impedance	$1 M\Omega \pm 1 \%$ with 14 pF ± 2 pF (meas.)		
	maximum input voltage at 1 $M\Omega$	$300 \text{ V (RMS)}, 400 \text{ V (V}_p),$ derates at 20 dB/decade to 5 V (RMS) above 250 kHz		
	trigger level	±5 V		
	sensitivity	> 300 mV (V <sub>DD</sub> )		
	coupling	DC, AC, LF reject		
Trigger output	functionality	A pulse is generated for every acquisition trigger event.		
	output voltage			
	at high impedance	0 V to 4.8 V		
	at 50 Ω	0 V to 2.4 V		
	pulse polarity	high active		

#### **Waveform measurements**

Automatic measurements	measurements on channels, math waveforms, reference waveforms	burst width, count positive pulses, count negative pulses, count falling edges, count rising edges, mean value, RMS cycle, RMS, mean cycle, peak peak, peak+, peak-, frequency, period, amplitude, top level, base level, positive overshoot, negative overshoot, pulse width+, pulse width-, duty cycle+, duty cycle-, rise time, fall time, delay, phase, crest factor, slew rate+, slew rate-, σ.std. deviation, σ.std. deviation cycle
	reference levels	lower, middle and upper level in percentage
	statistics	maximum, minimum, mean, standard deviation and measurement count for each automatic measurement
	number of active measurements	8
Cursor measurements	type	vertical, horizontal, vertical and horizontal, V-marker
	functions	x and y tracking, coupling of cursors, set to trace, two sources selectable
Quick measurements	function	fast overview of measurements from one channel, some measurements displayed with result lines in diagram
	sources	
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4
	measurements displayed in diagram	mean, max. peak, min. peak, rise time, fall time
	numerically displayed measurements	RMS cycle, peak-to-peak voltage, period, frequency

# **Digital voltmeter**

Accuracy		related to channel settings of voltmeter
		source
Measurements		DC, AC+DC RMS, AC RMS
Sources	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4
Number of measurements		up to 4
Resolution		up to 3 digits
Bandwidth		1 MHz

#### Counter

Measurements		frequency, period
Sources	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, trigger signal source
Number of measurements		2
Resolution		7 digits
Frequency range		0.05 Hz to bandwidth of oscilloscope
		(limited by bandwidth of trigger filter)

### Mask testing

Sources	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4
Mask definition		acquired waveform with user-defined tolerance, can be stored and restored
Result statistics		completed acquisitions, passed and failed acquisitions (absolute and in percent), test duration
Actions on mask violation		sound, acquisition stop, screenshot, save waveform, pulse out (AUX OUT connector)
Captured segments		all segments, failed segments

#### **Waveform maths**

Number of math equations		up to 5
Functions		addition, subtraction, multiplication,
		division, square, square root, absolute
		value, reciprocal, inverse, log10, ln,
		derivation, integration, low pass, high
		pass, track period, track frequency, track
		pulse width, track duty cycle
	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, math waveforms 1 to 4

# Fast Fourier transform (FFT)

Sources	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, math waveforms, references
Setup parameters		start frequency, stop frequency, center
		frequency, frequency span, vertical scale,
		vertical position, resolution bandwidth,
		gate (time range and position)
Windows		Hanning, Hamming, Blackman,
		rectangular, flat top
Waveform arithmetic		none, min. hold, max. hold, average
		(selectable 2 to 1024)
Scaling		dBm, dBV, dBμV, V (RMS)

#### **Search function**

Functions	search types	edge, width, peak, rise/fall time, runt, data2clock, pattern, window, protocol (available with R&S®RTA-K3, R&S®RTA-K6 and R&S®RTA-K7 options)
	configuration	manual level setting on screen, level with selectable hysteresis
	display of search events	up to 10 000 events in diagram and in result table
	markers on search events	up to 32 markers
	navigation in search events (stop mode)	knob (if result table is active)
Sources	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4, math waveforms from 1 to 5,
		D15 to D0 (with R&S®RTA-B1 option)

### **Display characteristics**

Diagram types	manually changeable vertical window size	Yt, XY, zoom, FFT, spectrogram (with R&S®RTA-K18 option)
XY mode		parallel display of XY diagram and Yt diagrams of input signals for X, Y
Zoom		horizontal and vertical zoom, split screen with overview signal and zoomed signal
Interpolation		sin(x)/x, linear, sample & hold
FFT mode		split screen with Yt diagrams and dedicated frequency diagram, spectrogram (with R&S®RTA-K18 option)
Waveform display		lines, dots only
Persistence		50 ms to 12.8 s; infinite
Special display mode		inverse brightness, waveform color modes for analog channels (temperature, fire, rainbow)
Diagram grid		lines, reticle, none, with annotation, track grid
Reference signals		up to 4 reference signals

### **Protocol and logic**

Bus decode	number of bus signals	4 <sup>1</sup>
	bus types	parallel, parallel clocked
	R&S®RTA-K1 option	SSPI, SPI, I <sup>2</sup> C
	R&S®RTA-K2 option	UART/RS-232/RS-422/RS-485
	R&S®RTA-K3 option	CAN, LIN
	R&S®RTA-K5 option	I <sup>2</sup> S, LJ, RJ, TDM
	R&S®RTA-K6 option	MIL-STD-1553
	R&S®RTA-K7 option	ARINC 429
	display types	decoded bus, logical signal,
		frame table (depends on decoded bus)
	position and size	size and position on screen selectable
	data format of decoded bus	hex, decimal, binary, octal, ASCII

### History and segmented memory

Acquisition memory		automatic, predef	ined manual	
Acquisition memory	tti-		•	
	automatic		nt size and numbers	5
	predefined		automatic numbers	
	manual	user-defined size	and numbers	
Memory segmentation	function	memory segments for the acquisition		
	number of segments <sup>2</sup>	record length	segments	total memory
			(up to)	(per channel)
		5 ksample	87 380	436.9 Msample
		10 ksample	87 380	873.8 Msample
		20 ksample	43 690	873.8 Msample
		50 ksample	17 476	873.8 Msample
		100 ksample	9 708	970.8 Msample
		200 ksample	5 140	1028 Msample
		500 ksample	2 131	1065.5 Msample
		1 Msample	1 065	1065 Msample
		2 Msample	536	1072 Msample
		5 Msample	214	1070 Msample
		10 Msample	107	1070 Msample
		20 Msample	53	1060 Msample
		50 Msample	21	1050 Msample
		100 Msample	10	1000 Msample
		200 Msample	5	1000 Msample
	Segmentation is active on all analog and logic channels, protocol decoding and		col decoding and	
	spectrum analysis.	ŭ	.,	Ţ.

 $<sup>^{\</sup>rm 1}$  If a bidirectional bus is used (e.g. UART RX/TX or SPI MOSI/MISO), two bus decoders are occupied.

<sup>&</sup>lt;sup>2</sup> At interleaved mode.

Fast-segmented mode		continuous recording of waveforms in acquisition memory without interruption due to visualization; blind time between consecutive acquisitions less than 200 ns (up to 2 000 000 waveforms/s)	
History mode	function	function  The history mode always provides access to past acquisitions in the segmented memory.	
	timestamp resolution	3.2 ns	
	history player	replays the recorded waveforms; repetition possible; adjustable speed; manual next/previous segment; numerical segment number input	
	analyze options	overlay all segments, average all segments, envelope all segments	

### **Miscellaneous**

Save/recall	device settings	save and recall on internal file system or USB memory stick or on a PC via web
	reference waveforms	interface or USB-MTP save and recall on internal file system or USB memory stick or on a PC via web interface or USB-MTP
	waveforms	save on USB memory stick or download and save on a PC via web interface or USB-MTP, available file formats: BIN, CSV, TXT float (MSB/LSB first)
	screenshots	save on USB memory stick or download and save on a PC via web interface or USB-MTP, available file formats: BMP, PNG
	device settings	save and recall on internal file system or USB memory stick or on a PC via web interface or USB-MTP
Camera key		configurable camera key, actions on press:
	save screenshot	one-touch off
	one-touch	one or more from the list:     setup     screenshots (PNG, color)     waveforms (BIN-MSB, CI, display data)     references     search event table     bus table     statistics
Instrument security		secure erasure of internal file system and all settings
Menu languages		available menu languages:  English German French Spanish Italian Portuguese Czech Polish Russian Simplified Chinese Traditional Chinese Korean Japanese
Help		online help, available languages:  • English
Undo/Redo		deep Undo/Redo function

### Input and outputs

Front			
Channel inputs		BNC, for details see Vertical system	
	probe interface	auto detection of passive probes,	
		Rohde & Schwarz active probe interface	
External trigger input		BNC, for details see Trigger system	
	probe interface	auto detection of passive probes	
Waveform generator		BNC, for details see R&S®RTA-B6,	
(requires R&S®RTA-B6 option)		waveform generator,	
		demo lug and GND lug	
Probe compensation output	signal shape	rectangle	
	frequency	1 kHz	
	voltage	$V_{low} = 0 \text{ V}, V_{high} = 1.5 \text{ V to } 3.3 \text{ V (meas.)}$	
Pattern source	P3 to P0	4 lugs, for details see R&S®RTA-B6,	
(requires R&S®RTA-B6 option)		4-bit pattern generator	
	frequency	1 mHz to 25 MHz	
	voltage	$V_{low} = 0 \text{ V}, V_{high} = 1.5 \text{ V to } 3.3 \text{ V (meas.)}$	
Ground lug		connected to ground	
USB host interface		1 port, type A plug, version 2.0,	
		flash drives only	
Rear			
Ethernet interface		1 port, 1 Gbit	
AUX OUT (BNC)	trigger out,	for details see Trigger system	
	reference frequency	10 MHz ±3.5 ppm (meas.)	
	mask violation	pulse	
USB device interface		1 port, type B plug, version 2.0	
Fixation loop		for securing the instrument with a cable	
Security slot		for standard Kensington style lock	
Right side			
Digital channel inputs	D15 to D8, D7 to D0	requires R&S®RTA-B1 option	

# General data

	10.1" WXGA display with capacitive touch
	1280 x 800 pixel (WXGA)
operating temperature range	0 °C to +50 °C
storage temperature range	–40 °C to +70 °C
·	+25 °C/+40 °C at 85 % rel. humidity cyclic,
	in line with IEC 60068-2-30
	up to 3000 m above sea level
	up to 4600 m above sea level
	up to 1000 iii above ood iovo.
sinusoidal	5 Hz to 150 Hz, max. 1.8 g at 55 Hz;
Sinasoidai	0.5 g from 55 Hz to 150 Hz,
	in line with EN 60068-2-6
	MIL-PRF-28800F, 4.5.5.3.2 sinusoidal
	•
	vibration, class 3 and 4
random	10 Hz to 300 Hz,
	acceleration 1.2 g (RMS),
	in line with EN 60068-2-64,
	MIL-PRF-28800F, 4.5.5.3.1 random
	vibration, class 3 and 4
	40 g shock spectrum,
	in line with MIL-STD-810E,
	method no. 516.4, procedure I,
	MIL-PRF-28800F, 4.5.5.4.1 functional
	shock, 30 g, 11 ms, halfsine
	in line with CISPR 11/EN 55011 group 1
	class A (for a shielded test setup);
	the instrument complies with the emission
	requirements stipulated by EN 55011,
	EN 61326-1 and EN 61326-2-1 class A,
	making the instrument suitable for use in
	3
	industrial environments
	industrial environments
	in line with IEC/EN 61326-1 table 2,
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup>
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup>
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC 1 year
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC 1 year  100 V to 240 V at 50 Hz to 60 Hz,
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC 1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>c</sub> CSA <sub>US</sub> , KC 1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC 1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC 1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, cCSA <sub>US</sub> , KC 1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC  1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A  max. 160 W  in line with  IEC 61010-1, IEC 61010-2-030  EN 61010-1, EN 61010-2-030  CAN/CSA-C22.2 No. 61010-1
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, cCSA <sub>US</sub> , KC 1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A max. 160 W in line with IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC  1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A  max. 160 W  in line with  IEC 61010-1, IEC 61010-2-030  EN 61010-1, EN 61010-2-030  CAN/CSA-C22.2 No. 61010-1
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC  1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A  max. 160 W in line with  IEC 61010-1, IEC 61010-2-030  EN 61010-1, EN 61010-2-030  CAN/CSA-C22.2 No. 61010-1  CAN/CSA-C22.2 No. 61010-2-030  UL 61010-1, UL 61010-2-030
W×H×D	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC  1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A  max. 160 W in line with  IEC 61010-1, IEC 61010-2-030  EN 61010-1, EN 61010-2-030  CAN/CSA-C22.2 No. 61010-1  CAN/CSA-C22.2 No. 61010-2-030  UL 61010-1, UL 61010-2-030
W×H×D	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC  1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A  max. 160 W in line with  IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030 CAN/CSA-C22.2 No. 61010-1 CAN/CSA-C22.2 No. 61010-2-030 UL 61010-1, UL 61010-2-030
	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC  1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A  max. 160 W  in line with  IEC 61010-1, IEC 61010-2-030  EN 61010-1, EN 61010-2-030  CAN/CSA-C22.2 No. 61010-1  CAN/CSA-C22.2 No. 61010-2-030  UL 61010-1, UL 61010-2-030  390 mm × 220 mm × 152 mm  (15.35 in × 8.66 in × 5.98 in)
W × H × D  without options (nom.) maximum sound pressure level at a	in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environments <sup>3</sup> VDE, <sub>C</sub> CSA <sub>US</sub> , KC  1 year  100 V to 240 V at 50 Hz to 60 Hz, 1.6 A to 0.7 A  max. 160 W in line with  IEC 61010-1, IEC 61010-2-030 EN 61010-1, EN 61010-2-030 CAN/CSA-C22.2 No. 61010-1 CAN/CSA-C22.2 No. 61010-2-030 UL 61010-1, UL 61010-2-030
	· • • · · · · · · · · · · · · · · · · ·

 $<sup>^3</sup>$  Test criterion is displayed noise level within  $\pm 1$  div for input sensitivity of 5 mV/div.

# **Options**

#### R&S®RTA-B1

ic channels	
	101:1 1 (
	16 logic channels (from D15 to D0)
	arranged in two logic probes with
	8 channels each, assignment of the logic
	probes to the channels D15 to D8 and D7
	to D0
	100 kΩ ± 2 %    ~4 pF (meas.) at probe tips
signal with minimum input voltage swing	400 MHz (meas.)
and hysteresis setting. Horman	±40 V (V <sub>p</sub> )
	500 mV (V <sub>pp</sub> ) (meas.)
	from D15 to D12, D11 to D8, D7 to D4 and
	D3 to D0
user range	±8 V in 25 mV steps
predefined	CMOS 2.5 V, TTL 1.4 V, ECL -1.3 V
	±(100 mV + 3 % of threshold setting)
	small, medium, large
range for each channel	±500 ns
	< 200 ps (meas.) for same vertical settings
	on the channels
two logic probes	2.5 Gsample/s on each channel
one logic probe	5 Gsample/s on each channel
	100 Msample for every channel
one logic probe	200 Msample for every channel
	see chapter Trigger system of the base unit
	all channels from D15 to D0
	positive pulse width, negative pulse width,
	period, frequency, burst width, delay,
	phase, positive duty cycle, negative duty
	cycle, positive pulse count, negative pulse
	count, rising edge count, falling edge
	count
	display of hex. value at the cursor position
I	purples
	independent of the oscilloscope
	acquisition, the state (stays low, stays high
	or toggles) of the channels from D15 to D0
	signal with minimum input voltage swing and hysteresis setting: normal  user range predefined  range for each channel

### R&S®RTA-B6

Waveform generator and 4-bit patter	ii generator		
Waveform generator		14 bit	
Resolution			
Sample rate		250 Msample/s	
Output impedance	II	50 Ω ±1 % (meas.)	
Amplitude	level	22 14: 4214 (4.1)	
	in to high Z	20 mV to 10 V (V <sub>pp</sub> )	
	in to 50 Ω	10 mV to 5 V (V <sub>pp</sub> )	
	accuracy	1.5 %	
DC offset	level		
	in to high Z	± 5 V	
	in to 50 Ω	± 2.5 V	
	accuracy	1.5 % or ±3 mV whatever is greater	
Sine	frequency	0.1 Hz to 25 MHz	
	SFDR	> 40 dBc (meas.)	
	THD	> 40 dBc (meas.)	
Rectangle	frequency	0.1 Hz to 10 MHz	
Pulse	frequency	0.1 Hz to 10 MHz	
4.60	edge time	adjustable	
	duty cycle	1 % to 99 %	
Ramp, triangle, sinc, exponential	frequency	0.1 Hz to 1 MHz	
Arbitrary	sample rate	max. 10 Msample/s	
Abiliary			
Nai-a	memory depth	32k point	
Noise	bandwidth	max. 25 MHz	
	level	0 to 100 % of signal amplitude	
Modulation	AM		
	function	sine, rectangle, triangle, ramp	
	frequency	0.1 Hz to 1 MHz	
	depth	0 to 100 %	
	FM		
	function	sine, rectangle, triangle, ramp	
	frequency	0.1 Hz to 1 MHz	
	deviation	depends on modulation frequency	
	ASK	, ,	
	function	sine, rectangle, triangle, ramp	
	frequency	0.1 Hz to 1 MHz	
	ASK depth	0 to 100 %	
	FSK	0 10 100 70	
	function	sine, rectangle, triangle, ramp	
		0.1 Hz to 1 MHz	
	frequency	11	
	FSK rate	0.1 Hz to carrier frequency/2	
Sweep	start frequency	1 Hz to 25 MHz	
	stop frequency	1 Hz to 25 MHz	
	sweep time	1 ms to 10 s	
	sweep type	linear, logarithmic, triangle	
Burst	number of cycle	1 to 1024	
	idle time	28 ns to 17 s	
	start phase	0° to 360°	
	trigger	continuous, manually	
1-bit pattern generator	, 33	•	
Functions		probe adjust/square wave, bus signal	
		source 4-bit counter, programmable 4-b	
		pattern	
Bus signal source		SPI, I <sup>2</sup> C, UART, CAN, LIN, audio, PWM	
240 digital double	bandwidth	9600 bit/s to 1 Mbit/s	
1 bit counter			
4-bit counter	frequency	25 mHz to 50 MHz	
Programmable pattern	sample rate	20 ns to 1 s, up/down	
	square wave frequency	1 mHz to 500 kHz	
	memory depth	8096 bit per channel	
	pattern idle time	50 ns to 1 s	
	amplitude	$V_{low} = 0 \text{ V}, V_{high} = 1.5 \text{ V to } 3.3 \text{ V (meas.)}$	

Bus configuration	sources for SCL and SDA	sources for SCL and SDA		
·	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)		
	bit rate	up to 10 Mbps		
	size of address	7 bit or 10 bit		
	size of data	8 bit		
	label list	associate frame identifier with symbolic ID		
Trigger	trigger events	start, stop, restart, missing acknowledge, address (7 bit or 10 bit), data, address and data		
	offset for trigger on data	0 data byte to 4095 data byte		
	data pattern width	up to 3 sequential data byte		
Decode	displayed signals	bus signal, logic signal or both		
	color coding of bus signal	address, data, start, stop, ACK, NACK, error		
	displayed format of address	hex, symbolic ID (label list)		
	displayed format of data	ASCII, binary, decimal or hex		
SPI triggering and decoding				
Bus configuration	sources for CS, CLK, MOSI and MISO			
-	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)		
	bit rate	up to 25 Mbps		
	chip select (CS)	active low, active high or missing (SSPI)		
	clock (CLK) slope	rise or fall		
	data symbol size	1 bit to 32 bit		
	idle time for SSPI	12.8 ns to 26.8 ms		
Trigger	trigger events	start of frame, end of frame, bit number, data pattern		
	selectable bit number	0 to 4095		
	offset for trigger on data pattern	0 to 4095 bit		
	data pattern size	1 bit to 32 bit		
Decode	displayed signals	bus signal, logic signal or both		
	color coding of bus signal	data, start, stop, error		
	displayed format of data	ASCII, binary, decimal or hex		
	data decoding	MSB or LSB first		

UART/RS-232/RS-422/RS-485	triggering and decoding		
Bus configuration	source for RX and TX		
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)	
	bit rate	300 bps to 1 Mbps or user-selectable up to 6 Mbps	
	end of frame	timeout	
	signal polarity	idle low, idle high	
	data symbol size	5 bit to 9 bit	
	parity	none, even or odd	
	stop bits	1, 1.5 or 2	
	Idle time	up to 26.8 ms	
Trigger	trigger events	start bit, start of frame, symbol number, any symbol, pattern of symbols, parity error, stop bit error, break	
	offset for trigger on data symbol	0 to 4095 symbols	
	data symbol pattern width	1 to floor (32/symbol size) symbols	
Decode	displayed signals	bus signal, logic signal or both	
	color coding of bus signal	data, start, stop, error, parity	
	displayed format of data	ASCII, binary, decimal or hex	

CAN triggering and decoding		
Bus configuration	signal type	CAN_H, CAN_L
	bit rate	10/20/33.3/50/83.3/100/125/250/500/ 1000 kbps or user-selectable in range from 100 bps to 2 Mbps
	sampling point	10 % to 90 % within bit period
	label list	associate frame identifier with symbolic IE
Trigger	trigger events	start of frame, frame type, identifier, identifier + data, error condition (any combination of CRC error, bit stuffing error, form error and ACK error)
	identifier setup	frame type (data, remote or both), identifier type (11 bit or 29 bit); condition =, ≠, >, <; identifier selectable from label list
	data setup	data pattern up to 8 byte (hex or binary); condition =, $\neq$ , >, <
Decode	displayed signals	bus signal, logic signal or both
	color coding of bus signal	start of frame, identifier, DLC, data
	<b>3</b> · · · · · · · · · · · · · · · · · · ·	payload, CRC, ACK, end of frame, error frame, overload frame, CRC error, bit stuffing error, ACK error
	displayed format of data	hex, decimal, binary, ASCII
	frame table	decode results displayed as tabulated list errors highlighted in red; frame navigation data export as CSV file
Search	search events	frame, error, identifier, identifier + data, identifier + error
	frame event setup	start of frame, end of frame, overload frame, error frame, data ID 11 bit, data ID 29 bit, remote ID 11 bit, remote ID 29 bit
	error event setup	any combination of CRC error, bit stuffing error, form error and ACK error
	identifier setup	frame type (data, remote or both), identifier type (11 bit or 29 bit); condition =, ≠, >, <; identifier selectable from label list
	data setup	data pattern up to 8 byte (hex or binary); condition =, $\neq$ , >, <
	event table	search results displayed as tabulated list; event navigation
LIN triggering and decoding		
Bus configuration	version	1.3, 2.x or SAE J602; mixed traffic is supported
	bit rate	1.2/2.4/4.8/9.6/10.417/19.2 kbps or user- selectable in range from 100 bps to 5 Mbps
	polarity	active high or active low
	label list	associate frame identifier with symbolic ID
Trigger	source	,
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)
	trigger events	start of frame (sync break), identifier, identifier + data, wakeup frame, error condition (any combination of checksum error, parity error and sync field error)
	identifier setup	range from 0d to 63d; condition =, ≠, >, <; identifier selectable from label list
	data setup	data pattern up to 8 byte (hex or binary); condition =, $\neq$ , >, <

Decode	displayed signals	bus signal, logic signal or both
	color coding of bus signal	frame, frame identifier, parity, data
		payload, checksum, error condition
	displayed format of data	hex, decimal, binary, ASCII
	frame table	decode results displayed as tabulated list,
		errors highlighted in red; frame navigation;
		data export as CSV file
Search	search events	frame, error, identifier, identifier + data,
		identifier + error
	frame event setup	start of frame, wake up
	error event setup	any combination of checksum error, parity
		error and sync field error
	identifier setup	range from 0d to 63d; condition =, ≠, >, <;
		identifier selectable from label list
	data setup	data pattern up to 8 byte (hex or binary);
		condition =, ≠, >, <
	event table	search results displayed as tabulated list;
		event navigation

Audio (I <sup>2</sup> S, LJ, RJ, TDM) triggering Bus configuration	source (data, clock, word/sync)				
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)			
	thresholds	per-channel threshold (analog channels), per-group threshold (logic channels), assisted threshold configuration (find level)			
	bit rate	up to 30 Mbps			
	signal type	I <sup>2</sup> S standard, left justified, right justified, TDM			
	polarity	data: active high, active low; clock: rising edge, falling edge; word/sync: normal, inverted			
	word length	2 bit to 32 bit			
	bit order	most significant bit first (MSBF), least significant bit first (LSBF)			
	I <sup>2</sup> S-specific setup	, ,			
	first channel	left, right			
	LJ/RJ-specific setup	, · · <b>y</b>			
	first channel	left, right			
	channel offset	0 to 31 bit			
	TDM-specific setup	TDM-specific setup			
	number of channels	1 to 8			
	channel length	2 bit to 32 bit			
	channel offset	0 to (channel length – word length) bits			
	channel delay	0 to 31 bit			
Trigger	trigger events	data, window, word/sync, error condition			
TTIgge.	data setup	define individual value and condition for each audio channel; condition =, ≠, >, <, inside range, outside range, don't care; trigger when "all" or "any" audio channel conditions are met in single audio frame			
	window setup	audio channel setup same as data setup; user-defined window length up to 4 000 000 000 frames			
	word/sync setup	rising edge, falling edge			
Decode	displayed signals	bus signal, stacked bus signal, logic signal			
	color coding of bus signal	color-coded audio channels			
	displayed format of data	hex, signed decimal, binary, ASCII			
	frame table	decode results displayed as tabulated list with timestamp; frame navigation; data export as CSV file			
	track of audio waveform	displays audio channel content as a waveform that is time-correlated to the source signals; user can activate, scale and position each audio channel individually			

MIL-STD-1553 triggering and decoding		
Protocol configuration	source	
1 Totocol configuration	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)
	bit rate	standard bit rate (1 Mbit/s)
	polarity	normal, inverted
	label list	associate frame identifier with symbolic ID
	auto threshold setup	assisted threshold configuration
	timing	max response (4 µs to 200 µs)
Trigger	trigger event setup	sync, word, command word, status word,
riiggei	ingger event setup	command and data word, error condition
	sync cotup	all words, command/status word, data
	sync setup	word
	word setup	all words, command word, status word,
	word solup	data word
	command word setup (type: address/word)	RT address (condition =, ≠, ≥, ≤, in range, out of range); direction (T/R); subaddress
		(condition =, $\neq$ , $\geq$ , $\leq$ , in range, out of
		range); data word count (condition =, $\neq$ , $\geq$ ,
		≤, in range, out of range)
	command word setup (type: mode code)	RT address (condition =, ≠, ≥, ≤, in range,
	(i)po. modo oodo)	out of range); subaddress (0, 31 or either);
		mode code from labeled dropdown list
	status word setup	RT address; status flags (message error,
	ciatae wera cotap	instrumentation, service request,
		broadcast command, busy, subsystem
		flag, dynamic bus control, terminal flag)
		individually configurable (1, 0, don't care)
	command and data word setup	transmission type (BC-RT, RT-BC, BC-
		BC, mode code); RT address (condition =,
		≠, ≥, ≤, in range, out of range); subaddress
		(condition =, ≠, ≥, ≤, in range, out of
		range); data word count (condition =, $\neq$ , $\geq$ ,
		≤, in range, out of range); data pattern up
		to 4 words long (condition =, ≠, ≥, ≤, in
		range, out of range); payload data index
		(condition =)
	error condition setup	any combination of sync error, Manchester
	one comment comp	error, parity error, timing error (see
		protocol configuration)
Decode	display signals	bus signal; symbolic ID in bus signal when
		label list in use
	color coding	sync, RT address, subaddress, mode
	and the same	code, status bit field, data, error condition
	displayed format of data	hex, decimal, binary, ASCII
	frame table	decode results displayed as tabulated list,
		errors highlighted in red; frame navigation;
		data export as CSV file; column with
		symbolic ID when label list in use
Search	search events	word, command word, mode code, status
	33.3.1 010110	word, command and data word, error
	word setup	command, status, data
	command word setup	see trigger settings for "command word
	SSmana mora sotup	setup (type: address/word)"
	mode code setup	see trigger settings for "command word
	mode oode setup	set trigger settings for command word setup (type: mode code)"
	status word setup	see trigger settings for "status word setup"
	command and data word setup	see trigger settings for "command and
	command and data word setup	data word setup"
	error condition setup	all, sync, parity, manchester, timing
	onor condition setup	an, syric, panty, manchester, timing

ARINC 429 triggering and deco			
Protocol configuration	source		
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4, logic channels from D15 to D0 (with R&S®RTA-B1 option)	
	bit rate	high (100 kbit/s), low (12.5 kbit/s), or user-defined in range 10 kbit/s to 1 Mbit/s	
	polarity	A leg, B leg, normal, inverted	
	label list	associate numeric label with symbolic ID; optional definition of ARINC word format iterms of availability of label-specific SDI and SSM fields	
	auto threshold setup	assisted threshold configuration	
Trigger	trigger event setup	word, label, label and data, error condition transmission interval	
	word setup	word start, word stop	
	label setup	label (condition =, $\neq$ , $\geq$ , $\leq$ , in range, out of range)	
	data setup	data pattern up to 23 bit long (condition = ≠, ≥, ≤, in range, out of range); data bit offset; SDI (00,01,10,11); SSM (00,01,10,11); label list can be used to determine availability of trigger properties SSM and SDI for given label value	
	error condition setup	any combination of coding error, parity error, gap error	
	transmission interval setup	label (condition =); SDI (optional); time interval (condition >, <, in range, out of range)	
Decode	display signals	bus signal, logic signal or both; symbolic ID in bus signal when label list in use	
	color coding	word begin, word end, label, SDI, data, SSM, parity, error	
	displayed format of data	hex, decimal, binary, ASCII	
	frame table	decode results displayed as tabulated list errors highlighted in red; frame navigation data export as CSV file; column with symbolic ID when label list in use	
Search	search events	word, label, label and data, error condition	
	word setup	word start, word stop	
	label setup	see trigger settings for "label setup"	
	data setup	see trigger settings for "data setup"	
	error condition setup	coding error, parity error, gap error, any	

Spectrum analysis and spectrogra	am		
General	additional displays	displays spectrum traces and/or spectrogram	
Spectrum	sources		
	R&S®RTA4004	channel 1, channel 2, channel 3, channel 4	
	setup parameters	center frequency, frequency span, automatic RBW, resolution bandwidth, gate position, gate width, vertical scale, vertical position, spectrum mode	
	scaling	dBm, dBV, dBµV, V (RMS)	
	span	0.2 Hz to 1.2 GHz	
	resolution bandwidth	span/10 ≥ RBW ≥ span/1000	
	windows	flat top, Hanning, Hamming, Blackman, rectangular	
	trace types	normal, max. hold, min. hold, average	
	spectrum mode optimized for dynamic range of freq domain (disables time domain for the same channel)		
Spectrogram	color	rainbow, temp. color, monochrome	
Marker	peak marker search	standard search	
Wild No.	poak marker coaren	parameter: min. level	
		advanced search	
		parameter: min. level, excursion,	
		maximum width, distance to next peak	
	reference marker	selection via index or frequency range	
	markers on peak	up to 100 markers	
	sources	any spectrum trace	
	table	frequency and magnitude, absolute or	
		relative to reference marker	
	marker result display	indicated at wave form: level, frequency	
Cursor	measurements on spectrum traces	level, frequency, level and frequency, V-marker	
	additional actions for cursor	coupling of cursors, set to trace, set to screen, track scaling, set next and previous peak	
Spectrogram measurements	two time cursor	t1, t2, delta t, total time, relative time between segments	

Power analysis			
General description	The R&S®RTA-K31 power analysis option extends the R&S®RTA firmware with measurement functionality focused on switched mode power supplies (SMPS) and DC/DC converters.		
Input	quality	evaluation of power quality at an AC input; measures real power, apparent power, reactive power, power factor and phase angle of power, frequency, crest factor, RMS of voltage and current	
	harmonics	measures up to the 334th harmonic of the incoming line frequency; precompliance checking for IEC 61000-3-2 (A, B, C, D), RTCA DO-160, MIL-STD-1399, max. limit checks	
	inrush current	measures peak inrush current and electrical charge within up to 3 configurable measurement zones to analyze the inrush and post-inrush behavior	
	consumption	long term measurement of consumed power and energy to analyze nonperiodical signals of e.g. standby devices	
Switching/control loop	slew rate	The minimum and maximum slew rate of current or voltage is measured at start and end of the switching cycle.	
	modulation	measures modulation of switching frequency, duty cycle (±) and pulse width	
	dynamic on-resistance	measures resistance of the switching transistor(s) in active state	
Power path	efficiency	measures input and output power to calculate the efficiency of a power device	
	switching loss	measures switching loss and conduction loss of a power device	
	safe operating area (SOA)	checks violation of voltage and current limits in which a power device can operate without damage; current versus voltage view (linear or log); violation mask is user- defined and editable in linear and log-log	
		views; save/load of masks; export of mask violation data	
	turn on/off time	measures relationship between AC and DC current, when turning SMPS off and on	
Output	ripple	measures AC components of output voltage or current, AC RMS, mean, period, frequency, duty cycles, min./max./peak-to-peak amplitude	
	spectrum	FFT analysis of output, measurement of frequency peaks	
	transient response	This measurement captures the device behavior between the event of load changes and stabilization; includes peak (voltage, time), settling time, rise time, overshoot and delay	
Deskew	automated	By using the R&S®RT-ZF20 probe deskew and calibration test fixture and Rohde & Schwarz voltage and current probes, the skew between the signals is compensated automatically.	
Zero offset	automated	automatic compensation of input offset	
Reporting	Report data can be saved for every measurement. Report generation using user- selected test results from historical and current tests. Put repeated and/or different measurements in one report. R&S®Oscilloscope Report Creator can be downloaded from Rohde & Schwarz website free-of-charge.		

Frequency response analysis - I	Bode plot	
Stimulus	frequency mode	single sweep or repeated sweep
	frequency range	10 Hz to 25 MHz
	amplitude mode	fixed or amplitude profile
	amplitude level	20 mV to 10 V into high Z
		10 mV to 5 V into 50 Ω
Input and output sources	R&S®RTA4004	channel 1, channel 2, channel 3,
		channel 4
Number of test points		10 points to 500 points per decade
Dynamic range		typ. > 70 dB based on 0 dBm
		(630 mV ( $V_{pp}$ ) into 50 $\Omega$ ,
		gain noise < 1 dB, phase noise < 5°)
Measurement		dual pair of tracking gain and phase
		cursors
Diagram types	manually changeable vertical window size	parallel display of result window and input
		and output signal view
Result table		navigation and export functions
Scaling	during and after test	auto-scale and manual scaling and
		positioning

# **Ordering information**

Designation	Туре	Order No.
Choose your R&S®RTA4000 base model		
Oscilloscope, 200 MHz, 4 channels	R&S®RTA4004	1335.7700.04
Base unit (including standard accessories: 500 MHz passive probe pe	r channel, power cord)	
Choose your bandwidth upgrade		
Upgrade of R&S®RTA4004 oscilloscopes to 350 MHz bandwidth	R&S®RTA-B243	1335.7846.02
Upgrade of R&S®RTA4004 oscilloscopes to 500 MHz bandwidth	R&S <sup>®</sup> RTA-B245	1335.7852.02
Upgrade of R&S®RTA4004 oscilloscopes to 1 GHz bandwidth	R&S®RTA-B2410	1335.7869.02
Choose your options		
Mixed signal upgrade for non-MSO models, 400 MHz	R&S®RTA-B1	1335.7823.02
Arbitrary waveform and 4-bit pattern generator	R&S®RTA-B6	1335.7830.02
I <sup>2</sup> C/SPI serial triggering and decoding	R&S®RTA-K1	1335.7681.02
UART/RS-232/RS-422/RS-485 serial triggering and decoding	R&S®RTA-K2	1335.7698.02
CAN/LIN serial triggering and decoding	R&S®RTA-K3	1335.7717.02
Audio (I <sup>2</sup> S, LJ, RJ, TDM) triggering and decoding	R&S®RTA-K5	1335.7723.02
MIL-STD-1553 serial triggering and decoding	R&S®RTA-K6	1335.7730.02
ARINC 429 serial triggering and decoding	R&S®RTA-K7	1335.7746.02
Spectrum analysis and spectrogram <sup>4</sup>	R&S®RTA-K18	1335.7752.02
Power analysis	R&S®RTA-K31	1335.7769.02
Frequency response analysis (Bode plot)	R&S®RTA-K36	1335.7975.02
Application bundle 5, consists of the following options:	R&S®RTA-PK1	1335.7775.02
R&S®RTA-K1, R&S®RTA-K2, R&S®RTA-K3, R&S®RTA-K5,		
R&S <sup>®</sup> RTA-K6, R&S <sup>®</sup> RTA-K7, R&S <sup>®</sup> RTA-K18, R&S <sup>®</sup> RTA-K31,		
R&S®RTA-K36, R&S®RTA-B6		
Application bundle <sup>6</sup> , consists of the following options:	R&S®RTA-PK1US	1335.7998.02
R&S®RTA-K1, R&S®RTA-K2, R&S®RTA-K3, R&S®RTA-K5,		
R&S <sup>®</sup> RTA-K6, R&S <sup>®</sup> RTA-K7, R&S <sup>®</sup> RTA-K31, R&S <sup>®</sup> RTA-K36,		
R&S®RTA-B6		
Choose your additional probes		
Single-ended passive probes		
500 MHz, 10 MΩ, 10:1, 300 V, 10 pF, 5 mm	R&S®RT-ZP05S	1333.2401.02
500 MHz, 10 MΩ, 10:1, 400 V, 9.5 pF, 2.5 mm	R&S <sup>®</sup> RT-ZP10	1409.7550.00
38 MHz, 1 MΩ, 1:1, 55 V, 39 pF, 2.5 mm	R&S®RT-ZP1X	1333.1370.02
Active broadband probes: single-ended		·
1.0 GHz, 10:1, 1 MΩ, BNC interface	R&S®RT-ZS10L	1333.0815.02
1.0 GHz, active, 1 MΩ, Rohde & Schwarz probe interface	R&S®RT-ZS10E	1418.7007.02
1.0 GHz, active, 1 MΩ, R&S®ProbeMeter, micro button,	R&S®RT-ZS10	1410.4080.02
Rohde & Schwarz probe interface		
1.5 GHz, active, 1 MΩ, R&S®ProbeMeter, micro button,	R&S®RT-ZS20	1410.3502.02
Rohde & Schwarz probe interface		
Active broadband probes: differential		'
1.0 GHz, active, differential, 1 MΩ, R&S®ProbeMeter, micro button,	R&S®RT-ZD10	1410.4715.02
incl. 10:1 external attenuator, 1 MΩ, 70 V DC, 46 V AC (peak),		
Rohde & Schwarz probe interface		
1.5 GHz, active, differential, 1 MΩ, R&S®ProbeMeter, micro button,	R&S®RT-ZD20	1410.4409.02
Rohde & Schwarz probe interface		
Power rail probe		
2.0 GHz, 1:1, 50 kΩ, ±0.85 V, ±60 V offset, Rohde & Schwarz probe	R&S®RT-ZPR20	1800.5006.02
interface		
High voltage single-ended passive probes		
250 MHz, 100:1, 100 MΩ, 850 V, 6.5 pF	R&S®RT-ZH03	1333.0873.02
400 MHz, 100:1, 50 MΩ, 1000 V, 7.5 pF	R&S®RT-ZH10	1409.7720.02
400 MHz, 1000:1, 50 MΩ, 1000 V, 7.5 pF	R&S®RT-ZH11	1409.7737.02

 $<sup>^4~{\</sup>rm The~R\&S^@RTA\text{-}K18}$  option is not distributed in North America.

 $<sup>^{\</sup>rm 5}~$  The R&S $^{\rm @}$ RTA-PK1 option is not distributed in North America.

 $<sup>^{\</sup>rm 6}~$  The R&S $^{\rm 8}$ RTA-PK1US option is only distributed in North America.

Designation	Туре	Order No.
High voltage probes: differential		
25 MHz, 20:1/200:1, 4 MΩ, 1.4 kV (CAT III), BNC interface	R&S®RT-ZD002	1337.9700.02
25 MHz, 10:1/100:14 MΩ, 700 V (CAT II), BNC interface	R&S®RT-ZD003	1337.9800.02
100 MHz, 8 MΩ, 1 kV (RMS) (CAT III), BNC interface	R&S®RT-ZD01	1422.0703.02
200 MHz, 10:1, ±20 V, BNC interface	R&S®RT-ZD02	1333.0821.02
800 MHz, 10:1, 200 kΩ, ±15 V, BNC interface	R&S®RT-ZD08	1333.0838.02
200 MHz, 250:1/25:1, 5 MΩ, 750 V (peak), 300 V CAT III,	R&S®RT-ZHD07	1800.2307.02
Rohde & Schwarz probe interface		
100 MHz, 500:1/50:1, 10 M $\Omega$ , 1500 V (peak), 1000 V CAT III,	R&S®RT-ZHD15	1800.2107.02
Rohde & Schwarz probe interface		
200 MHz, 500:1/50:1, 10 MΩ, 1500 V (peak), 1000 V CAT III,	R&S®RT-ZHD16	1800.2207.02
Rohde & Schwarz probe interface		
100 MHz, 1000:1/100:1, 40 MΩ, 6000 V (peak), 1000 V CAT III,	R&S®RT-ZHD60	1800.2007.02
Rohde & Schwarz probe interface		
Current probes	D. 0. 0. 0. 0. 0. 0. 0. 0. 0. 0. 0. 0. 0.	4000 0050 00
20 kHz, AC/DC, 0.01 V/A and 0.001 V/A, ±200 A and ±2000 A, BNC interface	R&S®RT-ZC02	1333.0850.02
100 kHz, AC/DC, 0.1 V/A, 30 A, BNC interface	R&S®RT-ZC03	1333.0844.02
2 MHz, AC/DC, 0.01 V/A, 500 A (RMS), Rohde & Schwarz probe	R&S®RT-ZC05B	1409.8204.02
interface		
10 MHz, AC/DC, 0.01 V/A, 150 A (RMS), BNC interface	R&S®RT-ZC10	1409.7750K02
10 MHz, AC/DC, 0.01 V/A, 150 A (RMS), Rohde & Schwarz probe	R&S®RT-ZC10B	1409.8210.02
interface		
50 MHz, AC/DC, 0.1 V/A, 30 A (RMS), Rohde & Schwarz probe	R&S®RT-ZC15B	1409.8227.02
interface	D0.08DT 7000	4.400.7700(/00
100 MHz, AC/DC, 0.1 V/A, 30 A (RMS), BNC interface	R&S <sup>®</sup> RT-ZC20 R&S <sup>®</sup> RT-ZC20B	1409.7766K02
100 MHz, AC/DC, 0.1 V/A, 30 A (RMS), Rohde & Schwarz probe interface	R&5°R1-2C20B	1409.8233.02
120 MHz, AC/DC, 1 V/A, 5 A (RMS), BNC interface	R&S®RT-ZC30	1409.7772K02
EMC near-field probes	R&S R1-2030	1409.7772K02
Probe set for E and H near-field measurements, 30 MHz to 3 GHz	R&S®HZ-15	1147.2736.02
Logic probes	100 HZ-15	1147.2730.02
400 MHz logic probe, 8 channels	R&S®RT-ZL04	1333.0721.02
Probe accessories	NGO NT ZEO+	1000.0721.02
Probe power supply for R&S®RT-ZC10/20/30	R&S®RT-ZA13	1409.7789.02
External attenuator 10:1, 2.0 GHz, 1.3 pF, 60 V DC,	R&S®RT-ZA15	1410.4744.02
42.4 V AC (peak) for R&S®RT-ZD20/30 probes	11.00	
Probe pouch	R&S®RT-ZA19	
Power deskew and calibration test fixture	R&S®RT-ZF20	1800.0004.02
3D positioner with central tensioning knob for easy clamping and	R&S®RT-ZA1P	1326.3641.02
positioning of probes (span width: 200 mm, clamping range: 15 mm)		
Choose your accessories		
Front cover	R&S®RTB-Z1	1333.1728.02
Soft bag	R&S®RTB-Z3	1333.1734.02
Transit case	R&S®RTB-Z4	1335.9290.02
Rackmount kit	R&S®ZZA-RTB2K	1333.1728.02

Warranty		
Base unit		3 years
All other items <sup>7</sup>		1 year
Options		
Extended warranty, one year	R&S®WE1	Please contact your local Rohde & Schwarz sales office.
Extended warranty, two years	R&S®WE2	
Extended warranty with calibration coverage, one year	R&S®CW1	
Extended warranty with calibration coverage, two years	R&S®CW2	
Extended warranty with accredited calibration coverage,	R&S®AW1	
one year		
Extended warranty with accredited calibration coverage,	R&S®AW2	
two years		

#### Extended warranty with a term of one and two years (WE1 and WE2)

Repairs carried out during the contract term are free of charge <sup>8</sup>. Necessary calibration and adjustments carried out during repairs are also covered.

#### Extended warranty with calibration (CW1 and CW2)

Enhance your extended warranty by adding calibration coverage at a package price. This package ensures that your Rohde & Schwarz product is regularly calibrated, inspected and maintained during the term of the contract. It includes all repairs <sup>8</sup> and calibration at the recommended intervals as well as any calibration carried out during repairs or option upgrades.

#### Extended warranty with accredited calibration (AW1 and AW2)

Enhance your extended warranty by adding accredited calibration coverage at a package price. This package ensures that your Rohde & Schwarz product is regularly calibrated under accreditation, inspected and maintained during the term of the contract. It includes all repairs <sup>8</sup> and accredited calibration at the recommended intervals as well as any accredited calibration carried out during repairs or option upgrades.

<sup>&</sup>lt;sup>7</sup> For options that are installed, the remaining base unit warranty applies if longer than 1 year. Exception: all batteries have a 1 year warranty.

<sup>&</sup>lt;sup>8</sup> Excluding defects caused by incorrect operation or handling and force majeure. Wear-and-tear parts are not included.

Version 06.00, May 2019

#### Service that adds value

- Uncompromising qualityLong-term dependability

#### Rohde & Schwarz

The Rohde & Schwarz electronics group offers innovative solutions in the following business fields: test and measurement, broadcast and media, secure communications, cybersecurity, monitoring and network testing. Founded more than 80 years ago, the independent company which is headquartered in Munich, Germany, has an extensive sales and service network with locations in more than 70 countries.

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#### Sustainable product design

- Environmental compatibility and eco-footprint
- Energy efficiency and low emissions
- Longevity and optimized total cost of ownership

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